

May 2013

# FDD86102

# N-Channel Shielded Gate PowerTrench<sup>®</sup> MOSFET 100 V, 36 A, 24 m $\Omega$

#### **Features**

- Shielded Gate MOSFET Technology
- Max  $r_{DS(on)}$  = 24 m $\Omega$  at  $V_{GS}$  = 10 V,  $I_D$  = 8 A
- Max  $r_{DS(on)}$  = 38 m $\Omega$  at  $V_{GS}$  = 6 V,  $I_D$  = 6 A
- High performance trench technology for extremely low r<sub>DS(on)</sub>
- High power and current handling capability in a widely used surface mount package
- Very low Qg and Qgd compared to competing trench technologies
- Fast switching speed
- 100% UIL tested
- RoHS Compliant

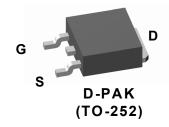


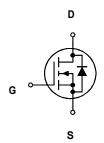
# **General Description**

This N-Channel MOSFET is produced using Fairchild Semiconductor's advanced PowerTrench process that incorporates Shielded Gate technology. This process has been optimized for  $r_{DS(on)}$ , switching performance and ruggedness.

# **Application**

■ DC - DC Conversion





## MOSFET Maximum Ratings T<sub>C</sub> = 25 °C unless otherwise noted

Symbol	Parameter			Ratings	Units
V <sub>DS</sub>	Drain to Source Voltage			100	V
V <sub>GS</sub>	Gate to Source Voltage			±20	V
	Drain Current -Continuous	T <sub>C</sub> = 25 °C		36	
I <sub>D</sub>	-Continuous	T <sub>A</sub> = 25 °C	(Note 1a)	8	Α
	-Pulsed		(Note 4)	75	
E <sub>AS</sub>	Single Pulse Avalanche Energy		(Note 3)	121	mJ
D	Power Dissipation	T <sub>C</sub> = 25 °C		62	W
$P_{D}$	Power Dissipation	T <sub>A</sub> = 25 °C	(Note 1a)	3.1	VV
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Junction Tempera	ature Range		-55 to +150	°C

#### **Thermal Characteristics**

$R_{\theta JC}$	Thermal Resistance, Junction to Case	2.0	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient (Note 1a)	40	C/VV

#### **Package Marking and Ordering Information**

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
FDD86102	FDD86102	D-PAK(TO-252)	13 "	12 mm	2500 units

# Electrical Characteristics T<sub>J</sub> = 25 °C unless otherwise noted

Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Off Chara	cteristics					
$BV_{DSS}$	Drain to Source Breakdown Voltage	$I_D = 250 \mu A, V_{GS} = 0 V$	100			V
$\frac{\Delta BV_{DSS}}{\Delta T_{J}}$	Breakdown Voltage Temperature Coefficient	$I_D$ = 250 $\mu$ A, referenced to 25 °C		67		mV/°C
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	V <sub>DS</sub> = 80 V, V <sub>GS</sub> = 0 V			1	μА
I <sub>GSS</sub>	Gate to Source Leakage Current	V <sub>GS</sub> = ±20 V, V <sub>DS</sub> = 0 V			±100	nA

#### On Characteristics (Note 2)

V <sub>GS(th)</sub>	Gate to Source Threshold Voltage	$V_{GS} = V_{DS}, I_{D} = 250 \mu A$	2	3.1	4	V
$\frac{\Delta V_{GS(th)}}{\Delta T_J}$	Gate to Source Threshold Voltage Temperature Coefficient	$I_D$ = 250 μA, referenced to 25 °C		-8.5		mV/°C
		V <sub>GS</sub> = 10 V, I <sub>D</sub> = 8 A		19	24	
r <sub>DS(on)</sub>	Static Drain to Source On Resistance	$V_{GS} = 6 \text{ V}, I_D = 6 \text{ A}$		26	38	mΩ
` ′		$V_{GS} = 10 \text{ V}, I_D = 8 \text{ A}, T_J = 125 ^{\circ}\text{C}$		33	44	
g <sub>FS</sub>	Forward Transconductance	V <sub>DS</sub> = 10 V, I <sub>D</sub> = 8 A		21		S

#### **Dynamic Characteristics**

C <sub>iss</sub>	Input Capacitance	.,	780	1035	pF
Coss	Output Capacitance	V <sub>DS</sub> = 50 V, V <sub>GS</sub> = 0 V, f = 1 MHz	180	240	pF
C <sub>rss</sub>	Reverse Transfer Capacitance	1 - 1 101112	15	25	pF
$R_g$	Gate Resistance		0.4		Ω

## **Switching Characteristics**

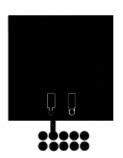
t <sub>d(on)</sub>	Turn-On Delay Time			7.6	15	ns
t <sub>r</sub>	Rise Time	V <sub>DD</sub> = 50 V, I <sub>D</sub> = 8 A,		3	10	ns
t <sub>d(off)</sub>	Turn-Off Delay Time	$V_{DD} = 50 \text{ V, } I_D = 8 \text{ A,}$ $V_{GS} = 10 \text{ V, } R_{GEN} = 6$	Ω	13.4	24	ns
t <sub>f</sub>	Fall Time			2.9	10	ns
$Q_{g}$	Total Gate Charge	V <sub>GS</sub> = 0 V to 10 V		13.4	19	nC
Qg	Total Gate Charge	$V_{GS} = 0 \text{ V to 5 V}$	<sub>DD</sub> = 50 V,	7.6	11	nC
$Q_{gs}$	Gate to Source Gate Charge	ID	= 8 A	4.0		nC
$Q_{gd}$	Gate to Drain "Miller" Charge			3.7		nC

#### **Drain-Source Diode Characteristics**

1Vob Source to Drain Diode Forward Voltage	Source to Drain Diode, Ferward Voltage	$V_{GS} = 0 \text{ V}, I_S = 8 \text{ A}$ (Note 2)	0.8	1.3	V
	V <sub>GS</sub> = 0 V, I <sub>S</sub> = 2.6 A (Note 2)	0.7	1.2	, v	
t <sub>rr</sub>	Reverse Recovery Time	I <sub>E</sub> = 8 A, di/dt = 100 A/μs	43	68	ns
Q <sub>rr</sub>	Reverse Recovery Charge	η <sub>F</sub> – 8 A, αι/αι – 100 Α/μ8	43	68	nC

#### Notes:

<sup>1.</sup>  $R_{\theta,JA}$  is the sum of the junction-to-case and case-to-ambient thermal resistance where the case thermal reference is defined as the solder mounting surface of the drain pins.  $R_{\theta,JC}$  is guaranteed by design while  $R_{\theta,JA}$  is determined by the user's board design.



a. 40 °C/W when mounted on a 1 in<sup>2</sup> pad of 2 oz copper.



 b. 96 °C/W when mounted on a minimum pad of 2 oz copper.

- 2. Pulse Test: Pulse Width < 300  $\mu\text{s},$  Duty cycle < 2.0%.
- 3. E<sub>AS</sub> 121 mJ is based on starting T<sub>J</sub> = 25 °C, L = 3 mH, I<sub>AS</sub> = 9 A, V<sub>DD</sub> = 100 V, V<sub>GS</sub> = 10 V. 100% test at L = 0.1 mH, I<sub>AS</sub> = 30 A.
- 4. Pulsed Drain current is tested at 300 µs with 2% duty cycle. For repetitive pulses, the pulse width is limited by the maximum junction temperature.

# Typical Characteristics T<sub>J</sub> = 25 °C unless otherwise noted

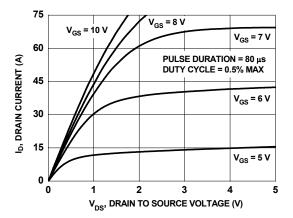


Figure 1. On-Region Characteristics

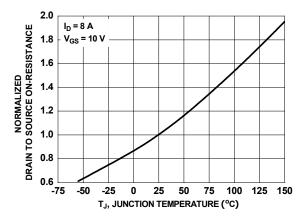


Figure 3. Normalized On-Resistance vs Junction Temperature

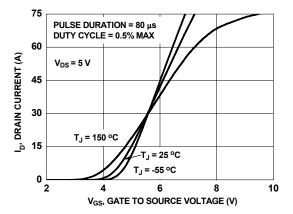


Figure 5. Transfer Characteristics

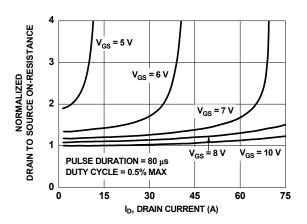


Figure 2. Normalized On-Resistance vs Drain Current and Gate Voltage

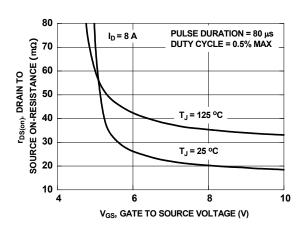


Figure 4. On-Resistance vs Gate to Source Voltage

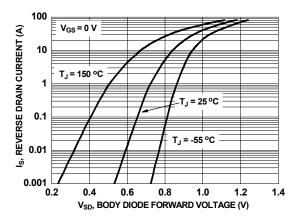


Figure 6. Source to Drain Diode Forward Voltage vs Source Current

# **Typical Characteristics** T<sub>J</sub> = 25 °C unless otherwise noted

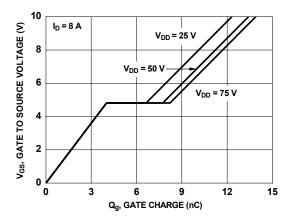


Figure 7. Gate Charge Characteristics

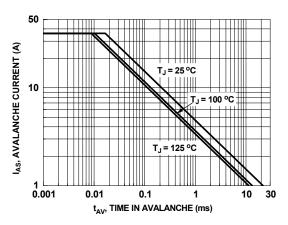


Figure 9. Unclamped Inductive Switching Capability

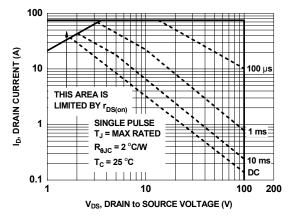


Figure 11. Forward Bias Safe Operating Area

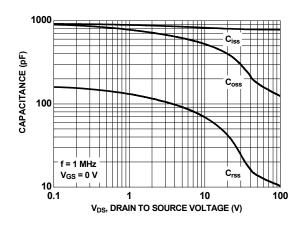


Figure 8. Capacitance vs Drain to Source Voltage

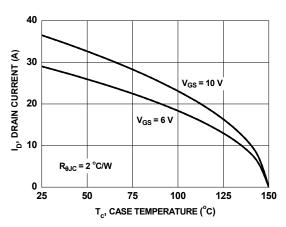


Figure 10. Maximum Continuous Drain Current vs Case Temperature

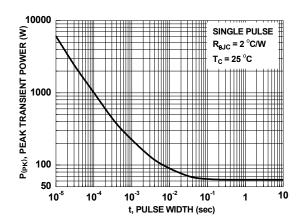


Figure 12. Single Pulse Maximum Power Dissipation

# Typical Characteristics T<sub>J</sub> = 25 °C unless otherwise noted

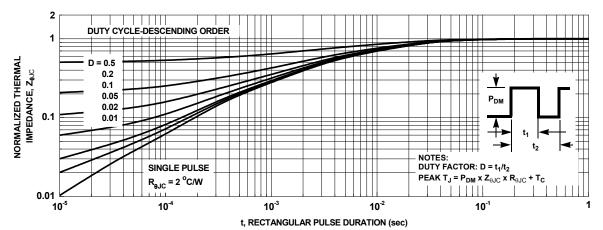


Figure 13. Junction-to-Case Transient Thermal Response Curve





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